

Atomic Resolution Analytical Electron Microscope

**JEM-ARM200F**

**NEOARM**

**e-ABF**

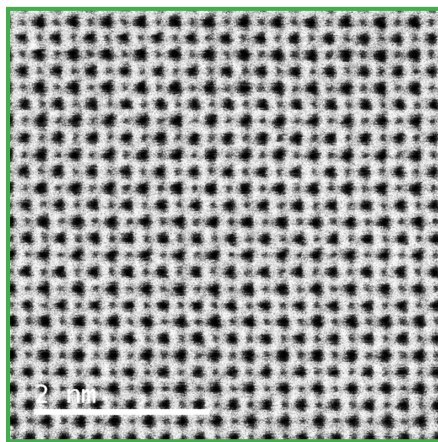
**(enhanced annular bright field image)**

An e-ABF is observable as a "live image" with real-time signal processing of ABF and BF signals and it shows enhanced contrast of light atoms.

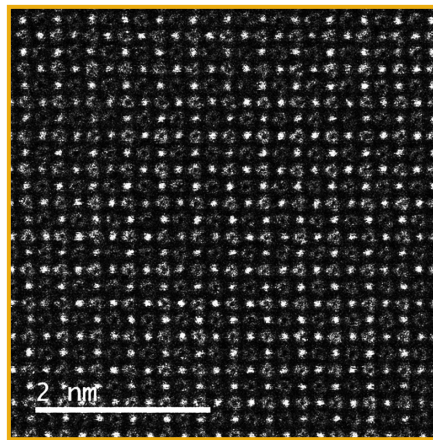


# e-ABF(enhanced annular bright field image)

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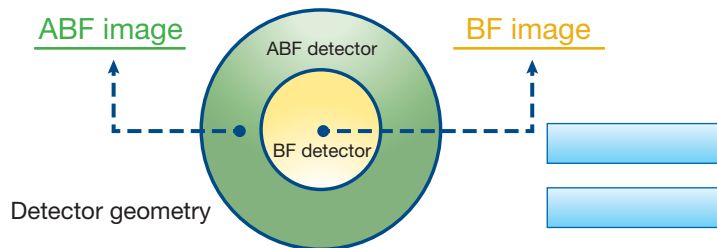
ABF



BF

e-ABF

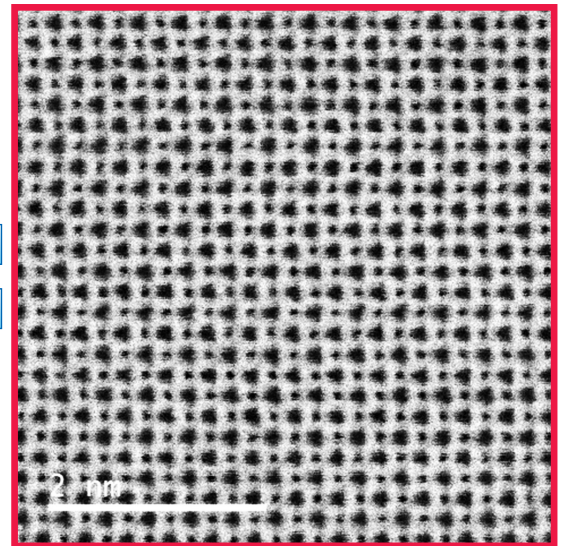
“Real time signal processing”



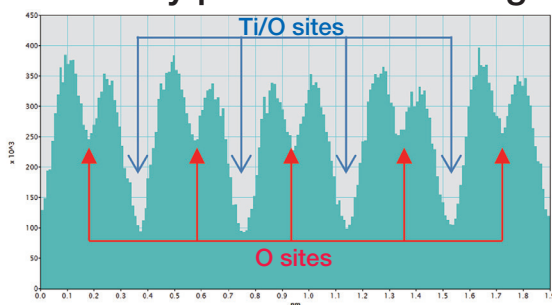
“Signal Processing”:  $ABF - BF = e-ABF$

Acc. Voltage : 200kV

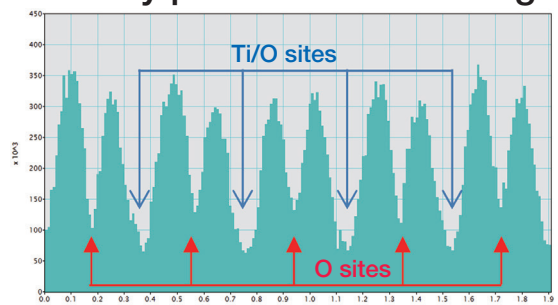
Sample : SrTiO<sub>3</sub>



Intensity profile of ABF image



Intensity profile of e-ABF image



Enhanced contrast of light atoms

Reference : S.D. Findlay, Y.Kohno, L.A.Cardamone, Y.Ikuhara, N.Shibata, Ultramicroscopy 136 (2014)31–41.

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